

Notic of References Cited	Application/Control No. 10/605,327	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Tuan T. Lam	Art Unit 2816	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,523,721	06-1996	Segawa et al.	330/86
	B	US-6,147,520	11-2000	Kothandaraman et al.	327/77
	C	US-6,549,075	04-2003	Zhang, Weibiao	330/282
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	5-347520	12-1993	Japan	-----	
	O	4-906	01-1992	Japan	-----	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	us 2002/0180507, Dec. 5, 2002, Yu et al.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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